# Power Inductor

#### **DFP252010TF-SERIES**

	ECN HISTORY LIST								
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN				
1.0	14/12/04	新 發 行	楊祥忠	詹偉特	林宜蕰				
備									
註									

### **Power Inductor**

**DFP252010TF-SERIES** 

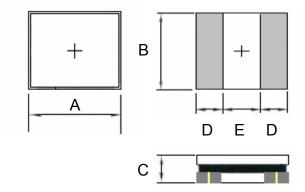
#### 1. Features

- 1. This specification applies Low Profile Power Inductors.
- 2. 100% Lead(Pb) & Halogen-Free and RoHS compliant.

#### 2. Dimension







Series	A(mm)	B(mm)	C(mm)	D(mm)	E(mm)
DFP252010TF	2.5 -0.1/+0.2	2.0 -0.10/+0.20	1.0Max	0.85 ref.	0.80 ref.

Units: mm

#### 3. Part Numbering



A: Series

B: Dimension

C: Lead Free Material
D: Inductance R47=0.47uH
E: Inductance Tolerance M=±20%

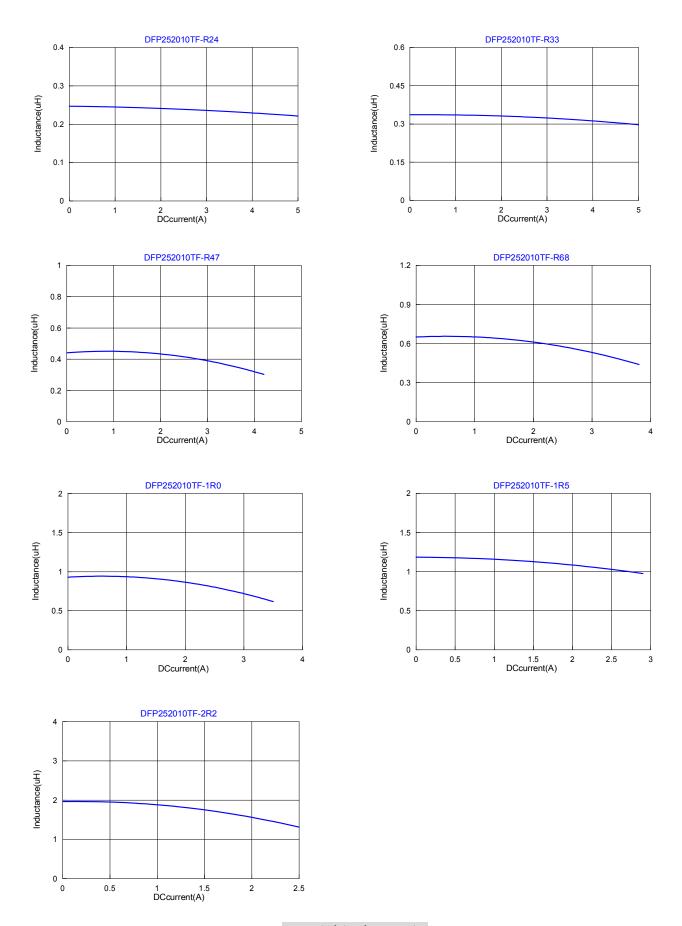
F:Control S/N

### 4. Specification

TAI-TECH Part Number	Inductance (uH)	Tolerance (%)	Test Frequency (Hz)	DCR (Ω) typ.	DCR (Ω) Max.	I sat (A) typ.	I sat (A) Max.	I rms (A) typ	I rms (A) Max.
DFP252010TF-R24M	0.24	±20%	0.1V/1M	0.029	0.041	4.89	4.38	3.67	3.16
DFP252010TF-R33M	0.33	±20%	0.1V/1M	0.031	0.043	4.38	3.87	3.57	3.06
DFP252010TF-R47M	0.47	±20%	0.1V/1M	0.033	0.045	4.08	3.36	3.47	2.96
DFP252010TF -R68M	0.68	±20%	0.1V/1M	0.045	0.054	3.77	2.96	3.36	2.85
DFP252010TF-1R0M	1.0	±20%	0.1V/1M	0.059	0.079	3.47	2.75	2.65	2.24
DFP252010TF-1R5M	1.5	±20%	0.1V/1M	0.089	0.107	2.75	2.14	2.35	1.94
DFP252010TF-2R2M	2.2	±20%	0.1V/1M	0.128	0.167	2.45	1.94	1.84	1.53

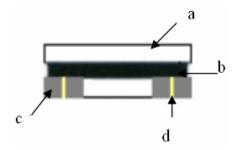
Note:

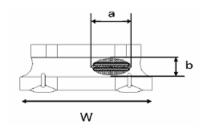
Isat : Based on inductance change  $\ (\triangle L/L0: \leq -30\%)$  @ ambient temp. 25°C



#### 5. Material List

No.	Description	Specification
a.	Core	Ferrite Core
b.	Coating	Epoxy with magnetic powder
С	Termination	Tin (Pb Free)
d	Wire	Enameled Copper Wire





Exposed wire tolerance limit of coating resin part on product side.

Size of exposed wire occurring to coating resin is specified below.

- 1. Width direction (dimension a): Acceptable when a  $\leq$  w/2 Nonconforming when a > w/2
- 2. Length direction (dimension b): Dimension b is not specified.
- 3. The total area of exposed wire occurring to each sides is not greater than 50% of coating resin area, and is acceptable.

#### 6. Reliability and Test Condition

Item	Performance	Test Condition				
Operating Temperature	-40~+125°C					
Storage Temperature (on board)						
Electrical Performance Test						
Inductance L	Refer to standard electrical characteristic list	Agilent-4291, Agilent-4287				
DC Resistance		Agilent-4338				
Rated Current	Base on temp. rise & △L/L0A≦30%.	Saturation DC Current (Isat) will cause L0 to drop approximately △L(%).				
Temperature Rise Test	ΔT 40°C Max	Heat Rated Current (Irms) will cause the coil temperature rise approximately $\triangle T({}^{\circ}\!$				

Item	Performance	Test Condition				
Mechanical Performance	Test					
Solder Heat Resistance	Appearance: No damage.  Inductance: within±10% of initial value  RDC: within±15% of initial value and shall not exceed the specification value	Temperature (°C) Time (s) Temperature ramp/immersion and emersion rate (°C) To the state cycles  260 ±5 (solder temp) 10 ±1 25mm/s±6 mm/s 1  Depth: completely cover the termination  Preheat: 150°C, 60 sec. • Solder: Sn99,5%-Cu0. 5% • Temperature: 245±5°C • Flux for lead free: Rosin. 9.5% • Dip time: 4±1 sec • Depth: completely cover the termination				
Solderability Test	More than 95% of terminal electrode should be covered with solder.					
Reliability Test						
Life Test		Preconditioning:Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles  Temperature: 85±2°C  Applied current: rated current  Duration: 1000±12hrs				
Thermal shock	Appearance: No damage.  Inductance: within±10% of initial value  RDC: within±15% of initial value and shall not exceed the specification value	Preconditioning:I J-STD-020DClas Step1: -40±2°C Step2: 25±2°C Step3: 105±2°C Number of cycles	Run through sification R 30±5min ≤0.5min 30±5min s: 500	re after placing for 1 IR reflow for 2 tin teeflow Profiles	nes.( IPC/JEDEC	
Humidity Resistance Test		J-STD-020DClas Humidity: 85±2 Temperature: 85 Duration: 1000h Measured at roon Preconditioning: I J-STD-020DClas	sification R  % R.H,  C±2°C  ars Min. wit a temperatu Run through sification R	h 100% rated curre re after placing for n IR reflow for 2 tin teflow Profiles	ent 24±2 hrs nes.( IPC/JEDEC	
Vibration Test		Equipment : V Total Amplitude	ibration ch :1.52mm±	10%	2 cycles each o	

#### 7. Soldering and Mounting

#### 7-1. Soldering

Mildly activated rosin fluxes are preferred. TAI-TECH terminations are suitable for all wave and re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

#### 7-1.1 Solder re-flow:

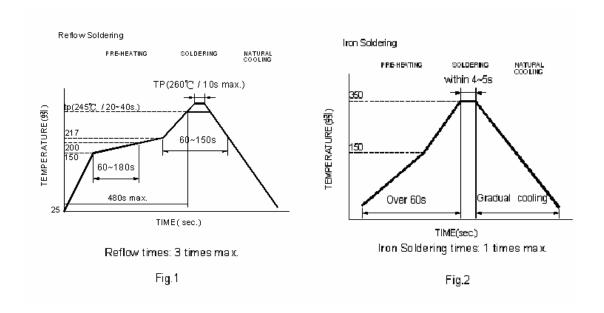
Recommended temperature profiles for re-flow soldering in Figure 1.

#### 7-1.2 Soldering Iron(Figure 2):

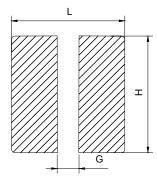
Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended.

- Preheat circuit and products to 150℃
- Never contact the ceramic with the iron tip
- · Use a 20 watt soldering iron with tip diameter of 1.0mm

- 355℃ tip temperature (max)
- 1.0mm tip diameter (max)
- Limit soldering time to 4~5 sec.



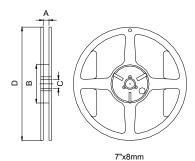
#### 7-2. Recommended PC Board Pattern



L(mm)	G(mm)	H(mm)	
2.9	0.8	2.4	

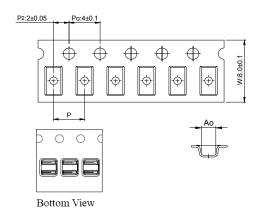
#### 8. Packaging Information

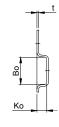
#### 8-1. Reel Dimension



Туре	A(mm)	B(mm)	C(mm)	D(mm)
7"x8mm	8.4±1.0	50 min.	13±0.8	178±2

#### 8-2. Tape Dimension / 8mm



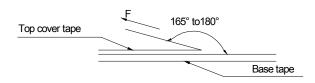


Series	Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)
DFP	252010	2.85±0.1	2.45±0.1	1.40±0.1	4.0±0.1	0.23±0.05

#### 8-3. Packaging Quantity

Chip size	252010
Chip / Reel	2000

#### 8-4. Tearing Off Force



The force for tearing off cover tape is 15 to 80 grams in the arrow direction under the following conditions.

Room Temp.	Room Humidity	Room atm	Tearing Speed
(℃)	(%)	(hPa)	mm/min
5~35	45~85	860~1060	300

#### **Application Notice**

- Storage Conditions(component level)
- To maintain the solderability of terminal electrodes:
- 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- ${\it 3. Bulk\ handling\ should\ ensure\ that\ abrasion\ and\ mechanical\ shock\ are\ minimized.}$



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# **Test Report**

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

桃園縣楊梅市幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI CITY, TAO-YUAN HSIEN. TAIWAN R. O. C.)

(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA) (桃園縣中壢市中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI CITY, TAOYUAN COUNTY 320, TAIWAN)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

樣品名稱(Sample Description)

SMD POWER INDUCTOR

樣品型號(Style/Item No.)

HPC(YHC, DR), MDC, FPC(YPC), FWP, SPC, SPI, UHP, DFP, DHP, TLPC, TLPH,

TLI SERIES

收件日期(Sample Receiving Date)

2014/11/10

測試期間(Testing Period)

2014/11/10 TO 2014/11/17

測試結果(Test Results) :

請見下一頁 (Please refer to next pages).



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#### 測試結果(Test Results)

測試部位(PART NAME)No.1

: 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鎬 / Cadmium (Cd)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合 電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
鋁 / Lead (Pb)	mg/kg	参考IEC 62321-5: 2013方法, 以感應耦合 電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4: 2013方法, 以感應耦合 電漿原子發射光譜儀檢測. / With reference to IEC 62321-4: 2013 and performed by ICP-AES.	2	n.d.
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	参考IEC 62321: 2008方法,以UV-VIS檢 測. / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.
绨 / Antimony (Sb)	mg/kg	參考US EPA 3052方法,以感應耦合電漿原子發射光譜儀檢測./With reference to US EPA Method 3052. Analysis was performed by ICP-AES.	2	n.d.
鈹 / Beryllium (Be)	mg/kg	参考US EPA 3052方法,以感應耦合電漿原子發射光譜儀檢測./With reference to US EPA Method 3052. Analysis was performed by ICP-AES.	2	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result)
				No.1
鄰苯二甲酸丁苯甲酯 / BBP (Butyl Benzyl phthalate) (CAS No.: 85-68-7)	%	参考EN 14372, 以氣相層析/質譜儀檢測. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二 (2-乙基己基)酯 / DEHP (Di- (2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	%	参考EN 14372, 以氣相層析/質譜儀檢測. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二異癸酯 / DIDP (Di- isodecyl phthalate) (CAS No.: 26761- 40-0; 68515-49-1)	%	参考EN 14372, 以氣相層析/質譜儀檢測. / With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.
鄰苯二甲酸二異壬酯 / DINP (Di- isononyl phthalate) (CAS No.: 28553- 12-0; 68515-48-0)	%	参考EN 14372, 以氣相層析/質譜儀檢測. / With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.
鄰苯二甲酸二正辛酯 / DNOP (Di-n- octyl phthalate) (CAS No.: 117-84-0)	%	參考EN 14372, 以氣相層析/質譜儀檢測. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	%	參考EN 14372, 以氣相層析/質譜儀檢測. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二異丁酯 / DIBP (Di- isobutyl phthalate) (CAS No.: 84-69- 5)	%	參考EN 14372, 以氣相層析/質譜儀檢測. / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
聚氟乙烯 / PVC	**	以紅外光譜分析及焰色法檢測./ Analysis was performed by FTIR and FLAME Test.	-	Negative

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値	結果 (Result)
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS-Acid, Metal Salt, Amide)	mg/kg	参考US EPA 3550C: 2007方法,以液相層析/質譜儀檢測. / With reference to US EPA 3550C: 2007. Analysis was	(MDL) 10	No.1
全氟辛酸 / PFOA (CAS No.: 335-67-1)	mg/kg	performed by LC/MS. 参考US EPA 3550C: 2007方法,以液相層析/質譜儀檢測. / With reference to US EPA 3550C: 2007. Analysis was performed by LC/MS.	10	n.d.
六溴環十二烷及所有主要被辨别出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified ( $\alpha$ - HBCDD, $\beta$ - HBCDD, $\gamma$ - HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	參考IEC 62321: 2008方法,以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 method. Analysis was performed by GC/MS.	5	n.d.
鹵素 / Halogen			***	
鹵素(氟)/ Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg		50	n.d.
鹵素(氣)/ Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg	参考BS EN 14582:2007, 以離子層析儀分析./ With reference to BS EN	50	n.d.
鹵素(溴)/ Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg	14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(碘)/ Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg		50	n.d.

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# **Test Report**

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑚科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
多溴聯苯總和 / Sum of PBBs	mg/kg			n.d.
一溴聯苯 / Monobromobiphenyl	mg/kg		5	n.d.
二溴聯苯 / Dibromobiphenyl	mg/kg		5	n.d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n.d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n.d.
五溴聯苯 / Pentabromobiphenyl	mg/kg		5	n.d.
六溴聯苯 / Hexabromobiphenyl	mg/kg		5	n.d.
七溴聯苯 / Heptabromobiphenyl	mg/kg		5	n.d.
入溴聯苯 / Octabromobiphenyl	mg/kg		5	n.d.
九溴聯苯 / Nonabromobiphenyl	mg/kg	参考IEC 62321: 2008方法,以氣相層析/ 質譜儀檢測./With reference to IEC 62321: 2008 and performed by GC/MS.	5	n.d.
十溴聯苯 / Decabromobiphenyl	mg/kg		5	n.d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg		_	n.d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg		5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg		5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg		5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg		5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg		5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg		5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg		5	n.d.
八溴聯苯醚 / Octabromodiphenyl ether	mg/kg		5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg		5	n.d.
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg		5	n.d.

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#### 備註(Note):

- 1. mg/kg = ppm ; 0.1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限値)
- 4. "-" = Not Regulated (無規格值)
- 5. \*\*= Qualitative analysis (No Unit) 定性分析(無單位)
- 6. Negative = Undetectable 陰性(未偵測到); Positive = Detectable 陽性(已偵測到)
- 7. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個别單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

#### PFOS参考資訊(Reference Information): 持久性有機污染物 POPs - (EU) 757/2010

PFOS濃度在物質或製備中不得超過0.001%(10ppm),在半成品、成品或零部件中不得超過0.1%(1000ppm),在紡織品或塗層材料中不得超過1 $\mu$ g/m²。

(Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above  $1\mu g/m^2$ .)

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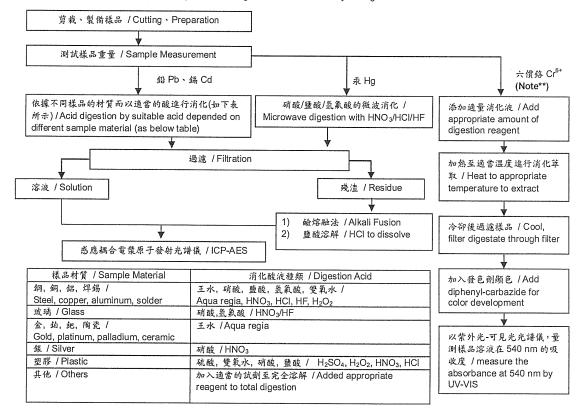
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- 1) 根據以下的流程圖之條件,樣品已完全溶解。( 六價錦測試方法除外 ) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (  $Cr^{6*}$  test method excluded )
- 2) 测試人員:楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 测試負責人: 張啓興 / Name of the person in charge of measurement: Troy Chang



Note\*\*:(1) 針對非金屬材料加入鹼性消化液,加热至 90~95℃萃取. / For non-metallic material, add alkaline digestion reagent and heat to 90~95℃.

(2) 針對金屬材料加入純水,加熱至沸騰萃取. / For metallic material, add pure water and heat to boiling.

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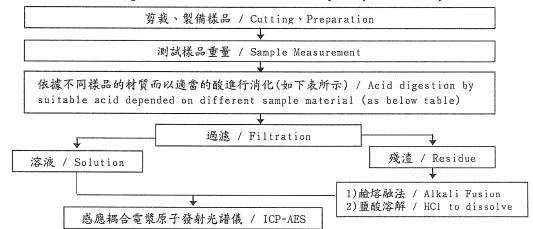
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- 1) 根據以下的流程圖之條件,樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.
- 2) 測試人員:楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang

#### 元素以 ICP-AES 分析的消化流程圖

(Flow Chart of digestion for the elements analysis performed by ICP-AES)



鋼,銅,鋁,焊錫 / Steel, copper, aluminum, solder	王水,硝酸,鹽酸,氫氟酸,雙氧水 /
	Aqua regia, HNO3, HC1, HF, H2O2
玻璃 / Glass	硝酸,氫氟酸 / HNO:/HF
金,鉑,鈀,陶瓷 / Gold, platinum, palladium, ceramic	王水 / Aqua regia
銀 / Silver	硝酸 / HNO3
塑膠 / Plastic	硫酸,雙氧水,硝酸,鹽酸 / HzSO4, HzOz, HNO3, HC1
其他 / Others	加入適當的試劑至完全溶解 / Added appropriate
	reagent to total digestion

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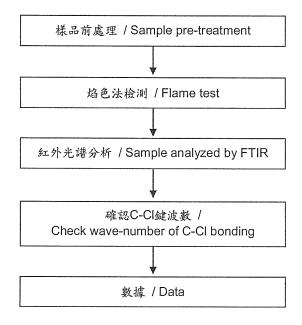
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#### 聚氯乙烯物質判定分析流程圖 /

#### Analysis flow chart for determination of PVC in material

- 測試人員:林建宇 / Name of the person who made measurement: Roy Lin
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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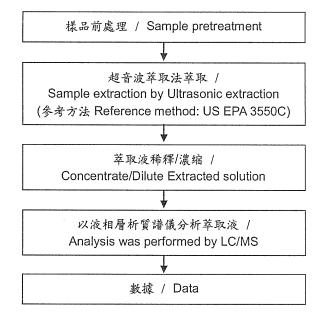
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#### 全氟辛酸/全氟辛烷磺酸分析流程圖 / PFOA/PFOS analytical flow chart

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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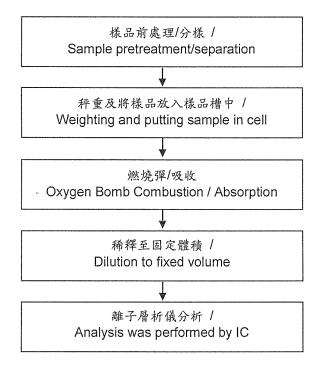
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#### 鹵素分析流程圖 / Analytical flow chart of halogen content

- 測試人員:陳恩臻 / Name of the person who made measurement: Rita Chen
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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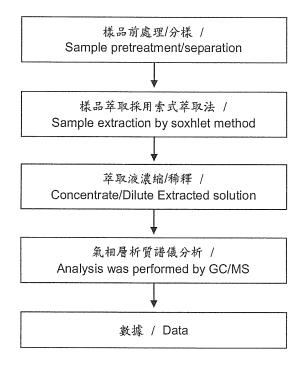
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#### 可塑劑分析流程圖 / Analytical flow chart of phthalate content

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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## **Test Report**

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

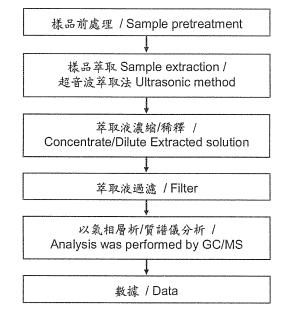
(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

桃園縣楊梅市幼獅工業區幼四路1號 (NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI CITY, TAO-YUAN HSIEN. TAIWAN R. O. C.)

(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA) (桃園縣中壢市中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI CITY, TAOYUAN COUNTY 320, TAIWAN)

#### 六溴環十二烷分析流程圖 / HBCDD analytical flow chart

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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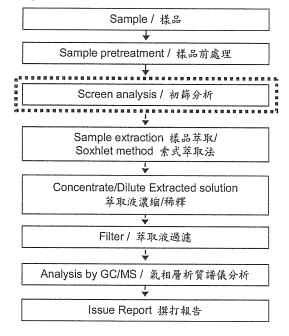
(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA) (桃園縣中壢市中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI CITY, TAOYUAN COUNTY 320, TAIWAN)

#### 多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang

初次測試程序 / First testing process ————

確認程序 / Confirmation process - · - · ▶



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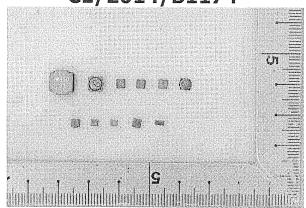
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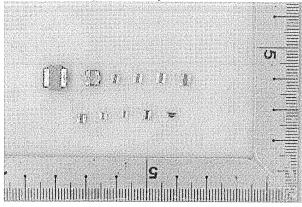
\* 照片中如有箭頭標示,則表示爲實際檢測之樣品/部位。\*

(The tested sample / part is marked by an arrow if it's shown on the photo.)

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\*\* 報告結尾 (End of Report) \*\*

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